

Substitute for form 1449A/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	10/631,284
		Filing Date	Concurrently Herewith
		First Named Inventor	Michael D. Brunsman
		Group Art Unit	2857
		Examiner Name	W. G. ...
Sheet	of	Attorney Docket Number	SC12818TS

U. S. PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Document Number Number - Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
W. G.	AA	6,211,541 B1	04/03/2001	Carroll et al.	C/411	Sub. 411
W. G.	AB	2002/0167304 A1	11/14/2002	Di Gregorio et al.	257	275
					324	158.1

FOREIGN PATENT DOCUMENTS							
Examine r Initials*	Cite No. ¹	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³	Number ⁴ Kind Code ² (if known)				

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
W. G.	AC	Kolding, "A Four-Step Method for De-Embedding Gigahertz On-Wafer CMOS Measurements," <i>IEEE Transactions on Electronic Devices</i> , April 2000, Vol. 47, No. 4, pp. 734-740.	
W. G.	AD	Koolen et al., "An Improved De-Embedding Technique for On-Wafer High-Frequency Characterization," <i>IEEE 1991 Bipolar Circuits and Technology Meeting 8.1</i> , 1991, pp. 188-191. (No month)	
W. G.	AE	Wu et al., "Unified Accurate CAD Models for RF, Microwave and Millimeter-Wave Integrated Circuits #," <i>Telsiks'99</i> , October 13-15, 1999, Nis, Yugoslavia, pp. 6-13.	

Examiner Signature	<i>W. G. Brunsman</i>	Date Considered	3-19-05
--------------------	-----------------------	-----------------	---------

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation, if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English Language Translation is attached.

If you need assistance in completing the form, call 1-800-PTO-9199 (1-800-786-9199) and select option 2.

